

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

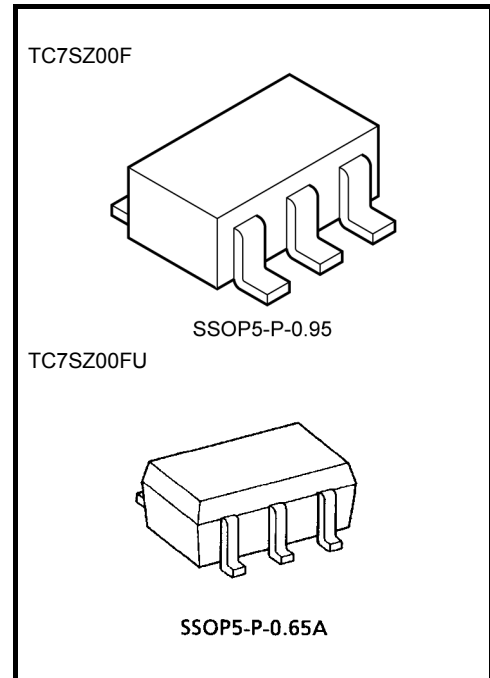
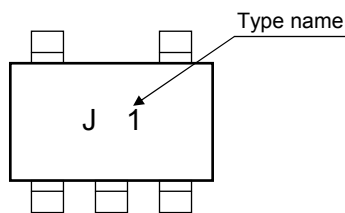
# TC7SZ00F, TC7SZ00FU

## 2 Input NAND Gate

### Features

- High output drive:  $\pm 24$  mA (min) at  $V_{CC} = 3$  V
- Super high speed operation:  $t_{pd} = 2.4$  ns (typ.)  
at  $V_{CC} = 5$  V, 50 pF
- Operation voltage range:  $V_{CC (opr)} = 1.8\sim 5.5$  V
- 5.5-V tolerant inputs
- 5.5-V power down protection outputs
- Matches the performance of TC74LCX series when operated at 3.3-V  $V_{CC}$

### Marking

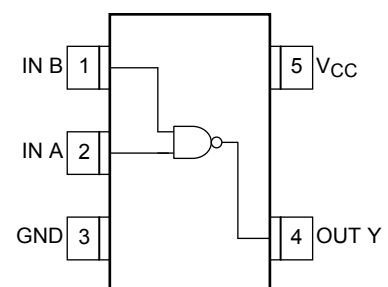


Weight  
 SSOP5-P-0.95 : 0.016 g (typ.)  
 SSOP5-P-0.65A : 0.006 g (typ.)

### Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Power supply voltage	$V_{CC}$	-0.5~6	V
DC input voltage	$V_{IN}$	-0.5~6	V
DC output voltage	$V_{OUT}$	-0.5~6	V
Input diode current	$I_{IK}$	-20	mA
Output diode current	$I_{OK}$	-20	mA
DC output current	$I_{OUT}$	$\pm 50$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 50$	mA
Power dissipation	$P_D$	200	mW
Storage temperature	$T_{stg}$	-65~150	$^\circ\text{C}$
Lead temperature (10s)	$T_L$	260	$^\circ\text{C}$

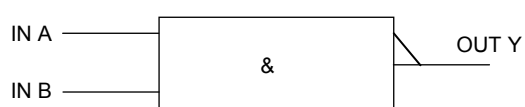
### Pin Assignment (top view)



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Logic Diagram



## Truth Table

Input		Output
A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

## Operating Ranges

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	1.8~5.5	V
		1.5~5.5 (Note 1)	
Input voltage	$V_{IN}$	0~5.5	V
Output voltage	$V_{OUT}$	0~5.5 (Note 2)	V
		0~ $V_{CC}$ (Note 3)	
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	dt/dv	0~20 ( $V_{CC} = 1.8\text{ V}, 2.5\text{ V} \pm 0.2\text{ V}$ )	ns/V
		0~10 ( $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$ )	
		0~5 ( $V_{CC} = 5.5\text{ V} \pm 0.5\text{ V}$ )	

Note 1: Data retention only

Note 2:  $V_{CC} = 0\text{ V}$

Note 3: High or Low state

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition	Ta = 25°C				Ta = -40~85°C		Unit	
			V <sub>CC</sub> (V)	Min	Typ.	Max	Min.	Max.		
High-level input voltage	V <sub>IH</sub>	—	1.8	V <sub>CC</sub> × 0.88	—	—	V <sub>CC</sub> × 0.88	—	V	
			2.3~5.5	V <sub>CC</sub> × 0.75	—	—	V <sub>CC</sub> × 0.75	—		
Low-level input voltage	V <sub>IL</sub>	—	1.8	—	—	V <sub>CC</sub> × 0.12	—	V <sub>CC</sub> × 0.12	V	
			2.3~5.5	—	—	V <sub>CC</sub> × 0.25	—	V <sub>CC</sub> × 0.25		
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	1.8	1.7	1.8	—	1.7	—	V
				2.3	2.2	2.3	—	2.2	—	
				3.0	2.9	3.0	—	2.9	—	
				4.5	4.4	4.5	—	4.4	—	
			I <sub>OH</sub> = -8 mA	2.3	1.9	2.15	—	1.9	—	
				3.0	2.4	2.8	—	2.4	—	
				4.5	2.3	2.68	—	2.3	—	
I <sub>OH</sub> = -16 mA	3.0	2.4	2.8	—	2.4	—				
	4.5	3.8	4.2	—	3.8	—				
	4.5	3.8	4.2	—	3.8	—				
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub>	I <sub>OL</sub> = 100 μA	1.8	—	0	0.1	—	0.1	V
				2.3	—	0	0.1	—	0.1	
				3.0	—	0	0.1	—	0.1	
				4.5	—	0	0.1	—	0.1	
			I <sub>OL</sub> = 8 mA	2.3	—	0.1	0.3	—	0.3	
				3.0	—	0.15	0.4	—	0.4	
				4.5	—	0.22	0.55	—	0.55	
			I <sub>OL</sub> = 16 mA	3.0	—	0.15	0.4	—	0.4	
				4.5	—	0.22	0.55	—	0.55	
				4.5	—	0.22	0.55	—	0.55	
I <sub>OL</sub> = 24 mA	3.0	—	0.22	0.55	—	0.55				
	4.5	—	0.22	0.55	—	0.55				
	4.5	—	0.22	0.55	—	0.55				
I <sub>OL</sub> = 32 mA	3.0	—	0.22	0.55	—	0.55				
	4.5	—	0.22	0.55	—	0.55				
	4.5	—	0.22	0.55	—	0.55				
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND	0~5.5	—	—	±1	—	±10	μA	
Power off leakage current	I <sub>OFF</sub>	V <sub>IN</sub> or V <sub>OUT</sub> = 5.5 V	0.0	—	—	1	—	10	μA	
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	5.5	—	—	2	—	20	μA	

**AC Characteristics (unless otherwise specified, Input:  $t_r = t_f = 3$  ns)**

Characteristics	Symbol	Test Condition	Ta = 25°C			Ta = -40~85°C		Unit	
			V <sub>CC</sub> (V)	Min	Typ.	Max	Min.		Max.
Propagation delay time	t <sub>pLH</sub>	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 1 MΩ	1.8	2.0	4.5	9.5	2.0	10.0	ns
			2.5 ± 0.2	0.8	3.0	6.5	0.8	7.0	
	3.3 ± 0.3		0.5	2.4	4.5	0.5	4.7		
	5.0 ± 0.5		0.5	2.0	3.9	0.5	4.1		
	t <sub>pHL</sub>		3.3 ± 0.3	1.5	2.9	5.0	1.5	5.2	
			5.0 ± 0.5	0.8	2.4	4.3	0.8	4.5	
Input capacitance	C <sub>IN</sub>	—	0~5.5	—	4	—	—	pF	
Power dissipation capacitance	C <sub>PD</sub>	(Note 4)	3.3	—	24	—	—	—	pF
			5.5	—	30	—	—	—	

Note 4: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

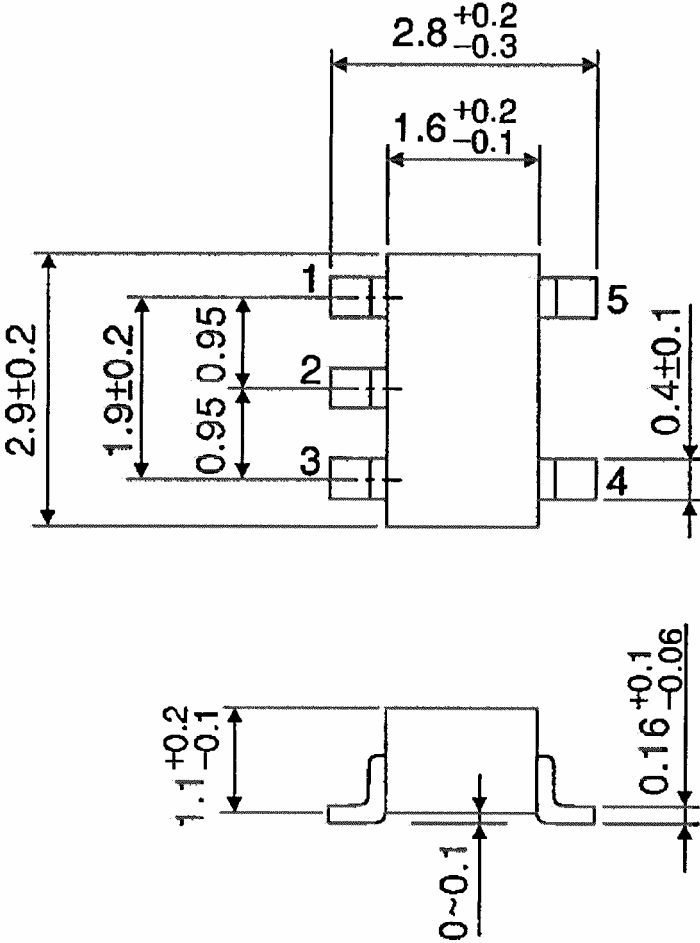
Average operating current can be obtained by the equation:

$$I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Package Dimensions

SSOP5-P-0.95

Unit : mm

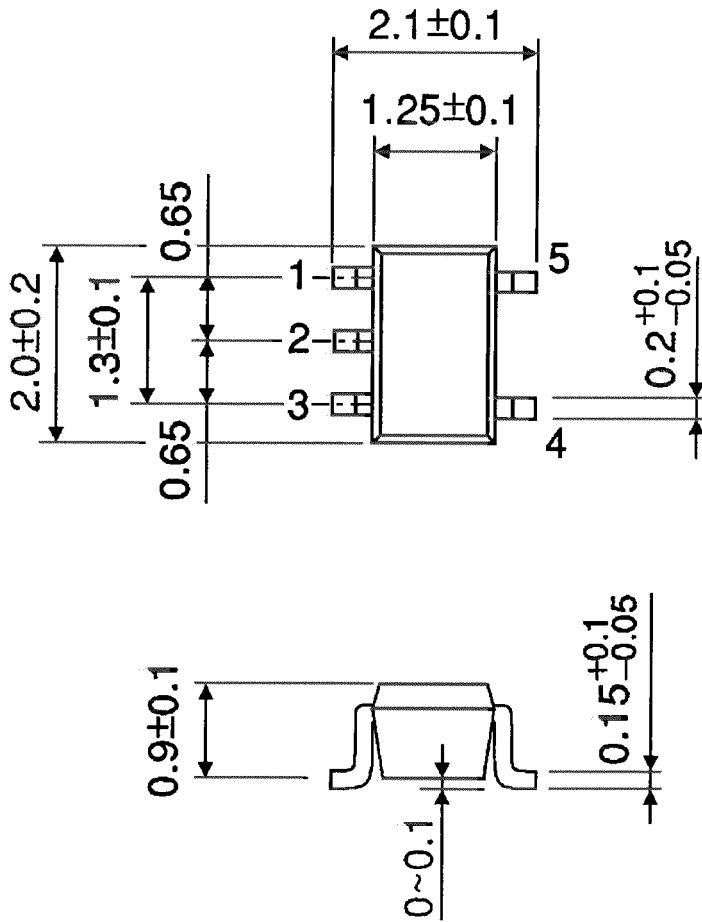


Weight: 0.016 g (typ.)

## Package Dimensions

SSOP5-P-0.65A

Unit : mm



Weight: 0.006 g (typ.)

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20070701-EN GENERAL

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